Characterization of High Power Devices
Wednesday Jan. 22, 9:00-17:00

Device characterization is an essential process in many aspects of research, development and testing of RF and microwave devices. To the inexperienced, this might seem intimidating or even scary. In this course, we will explore various interconnected topics of device characterization that form the amplifier design flow. Topics include pulsed IV and S-parameters for compact model extraction, load pull for model validation and measurement, amplifier design and IC stability analysis, X-parameter modeling and system-level simulations.

Register at http://rww2014device.eventbrite.com

The RWW Industrial Forum will include Wireless Apps (similar to uApps) and special hardware demonstrations given by researchers

Contact c.jackson@ieee.org for more information